TEST PROBE KIT

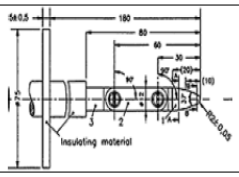
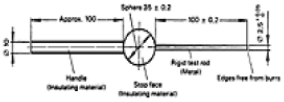
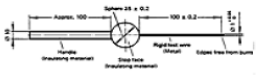
Model TPK-05: IEC 60529 - **IP Codes**

ED&D Test Probe Kits:

Several different accessibility test probe kits are available for specific standards. Kits can be created for other standards on request.

The **TPK-05** was designed to provide the probes required from IEC 60529, the IP Code standard. It includes the following:

- IEC Jointed Finger Probe (w/ banana jack in handle; as required) (TFP-01)
- 2.5 mm Test Rod (TRP-01)
- 1.0 mm Test Wire (TRP-02)
- Test Sphere Probe with handle (TSP-01)
- Test Sphere Probe (small) (TSP-02)
- NIST-traceable ISO/IEC 17025 Accredited Calibration Certificate. We are "in scope" and it specifically lists us for "Accessibility Probes"! (data is available separately)
- Custom-cut padded carrying case
- One year warranty
- Free expert level technical support

TFP-01		**This is the "International" test finger required by most IEC, EN and CSA Standards, in addition to many UL Standards. Built in strict accordance to the newest requirements - with integral palm simulator. This is the required Finger Probe available with a integral jack in the handle for continuity testing - as mandated by the IEC CB Scheme. Finger made of chrome-plated steel. All parts precision machined.**
TRP-01		**Used to verify the protection of persons against access to hazardous parts. Also used to verify the protection against access with a tool. Meets IEC and EN Standards including IEC 529 for IP3 and suffix C codes. The handle and stop face are made of Delrin. The rod is made of stainless steel.**
TRP-02		**Used to verify protection of persons against access with a wire. Meets IEC and EN Standards including IEC 529 for IP4 and suffix D codes. The handle and stop face are made of Delrin. The wire is made of stainless steel.**

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